

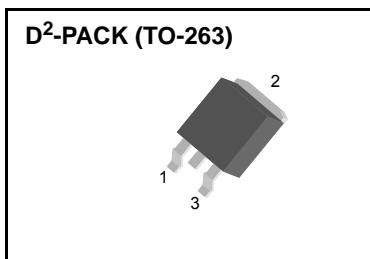
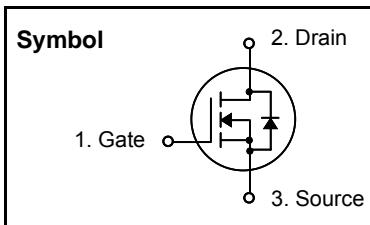
Logic N-Channel MOSFET

Features

- Low $R_{DS(on)}$ (0.0135Ω)@ $V_{GS}=10V$
- Low Gate Charge (Typical $21.5nC$)
- Low C_{RSS} (Typical $130pF$)
- Improved dv/dt Capability
- 100% Avalanche Tested
- Maximum Junction Temperature Range ($175^{\circ}C$)

General Description

This Power MOSFET is produced using SemiWell's advanced planar stripe, DMOS technology. This latest technology has been especially designed to minimize on-state resistance, have a low gate charge with superior switching performance, and rugged avalanche characteristics. This Power MOSFET is well suited for synchronous DC-DC Converters and Power Management in portable and battery operated products.



Absolute Maximum Ratings

Symbol	Parameter	Value	Units
V_{DSS}	Drain to Source Voltage	30	V
I_D	Continuous Drain Current(@ $T_C = 25^{\circ}C$)	60	A
	Continuous Drain Current(@ $T_C = 100^{\circ}C$)	43	A
I_{DM}	Drain Current Pulsed (Note 1)	240	A
V_{GS}	Gate to Source Voltage	± 20	V
E_{AS}	Single Pulsed Avalanche Energy (Note 2)	270	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	7.0	V/ns
P_D	Total Power Dissipation(@ $T_A = 25^{\circ}C$) *	3.75	W
	Total Power Dissipation(@ $T_C = 25^{\circ}C$)	100	W
	Derating Factor above $25^{\circ}C$	0.67	W/ $^{\circ}C$
T_{STG}, T_J	Operating Junction Temperature & Storage Temperature	-55 ~ 175	$^{\circ}C$
T_L	Maximum Lead Temperature for soldering purpose, 1/8 from Case for 5 seconds.	300	$^{\circ}C$

Thermal Characteristics

Symbol	Parameter	Value			Units
		Min.	Typ.	Max.	
R_{0JC}	Thermal Resistance, Junction-to-Case	-	-	1.50	$^{\circ}C/W$
R_{0JA}	Thermal Resistance, Junction-to-Ambient *	-	-	40	$^{\circ}C/W$
R_{0CA}	Thermal Resistance, Junction-to-Ambient	-	-	62.5	$^{\circ}C/W$

* When mounted on the minimum pad size recommended (PCB Mount)

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Electrical Characteristics ($T_C = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu\text{A}$	30	-	-	V
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temperature coefficient	$I_D = 250\mu\text{A}$, referenced to 25°C	-	0.02	-	$\text{V}/^\circ\text{C}$
I_{DSS}	Drain-Source Leakage Current	$V_{DS} = 30V, V_{GS} = 0V$	-	-	1	μA
		$V_{DS} = 24V, T_C = 150^\circ\text{C}$	-	-	10	μA
I_{GSS}	Gate-Source Leakage, Forward	$V_{GS} = 20V, V_{DS} = 0V$			100	nA
	Gate-Source Leakage, Reverse	$V_{GS} = -20V, V_{DS} = 0V$	-	-	-100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.0	-	3.0	V
$R_{DS(\text{ON})}$	Static Drain-Source On-state Resistance	$V_{GS} = 10V, I_D = 30A$	-	0.011	0.0135	Ω
		$V_{GS} = 5V, I_D = 30A$	-	0.015	0.019	Ω
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{GS} = 0V, V_{DS} = 25V, f = 1\text{MHz}$	-	1010	1320	pF
C_{oss}	Output Capacitance		-	450	585	
C_{rss}	Reverse Transfer Capacitance		-	130	170	
Dynamic Characteristics						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = 15V, I_D = 30A, R_G = 50\Omega$ ※ see fig. 13. (Note 4, 5)	-	20	50	ns
t_r	Rise Time		-	55	120	
$t_{d(off)}$	Turn-off Delay Time		-	53	116	
t_f	Fall Time		-	75	160	
Q_g	Total Gate Charge	$V_{DS} = 24V, V_{GS} = 5V, I_D = 60A$ ※ see fig. 12. (Note 4, 5)	-	21.5	28	nC
Q_{gs}	Gate-Source Charge		-	3.6	-	
Q_{gd}	Gate-Drain Charge(Miller Charge)		-	10.7	-	

Source-Drain Diode Ratings and Characteristics

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit.
I_S	Continuous Source Current	Integral Reverse p-n Junction Diode in the MOSFET	-	-	60	A
I_{SM}	Pulsed Source Current		-	-	240	
V_{SD}	Diode Forward Voltage	$I_S = 60A, V_{GS} = 0V$	-	-	1.5	V
t_{rr}	Reverse Recovery Time	$I_S = 60A, V_{GS} = 0V, dI_F/dt = 100A/\mu\text{s}$	-	40	-	ns
Q_{rr}	Reverse Recovery Charge		-	35	-	

※ NOTES

1. Repeatability rating : pulse width limited by junction temperature
2. $L = 75\mu\text{H}, I_{AS} = 60A, V_{DD} = 15V, R_G = 0\Omega$, Starting $T_J = 25^\circ\text{C}$
3. $ISD \leq 60A, di/dt \leq 300A/\mu\text{s}, V_{DD} \leq BV_{DSS}$. Starting $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$
5. Essentially independent of operating temperature.



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Fig 1. On-State Characteristics

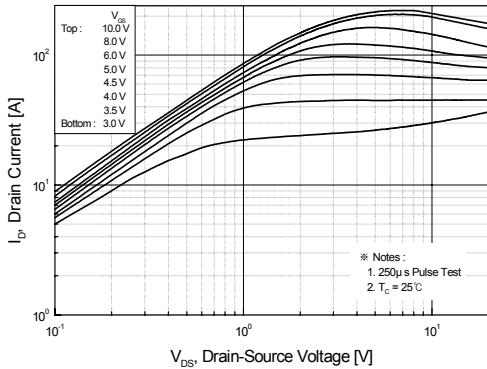


Fig 2. Transfer Characteristics

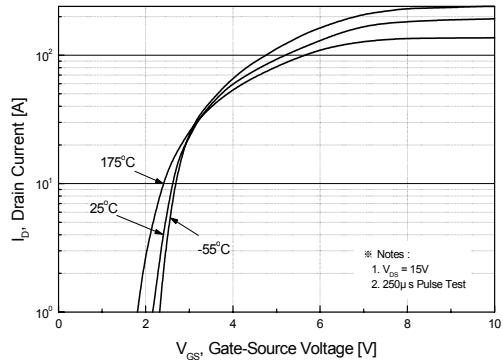


Fig 3. On Resistance Variation vs. Drain Current and Gate Voltage

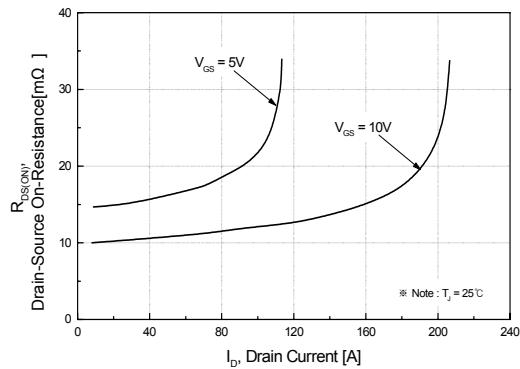


Fig 5. Capacitance Characteristics (Non-Repetitive)

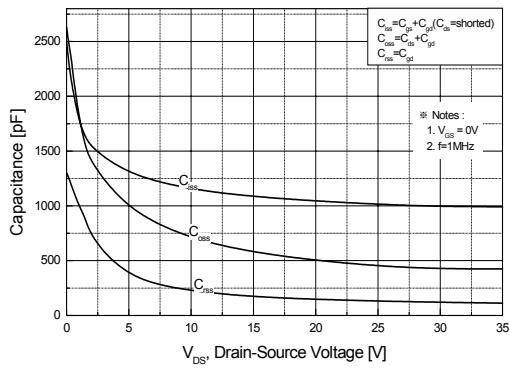


Fig 4. On State Current vs. Allowable Case Temperature

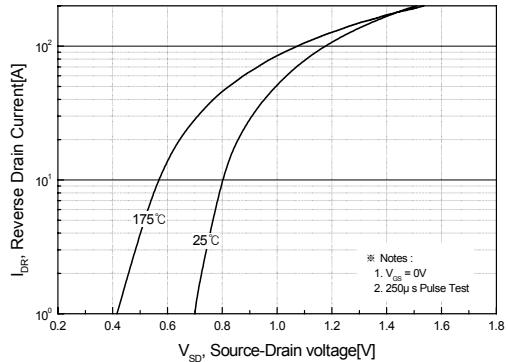
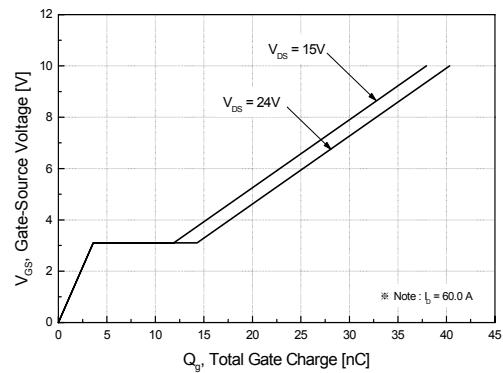


Fig 6. Gate Charge Characteristics



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Fig 7. Breakdown Voltage Variation vs. Junction Temperature

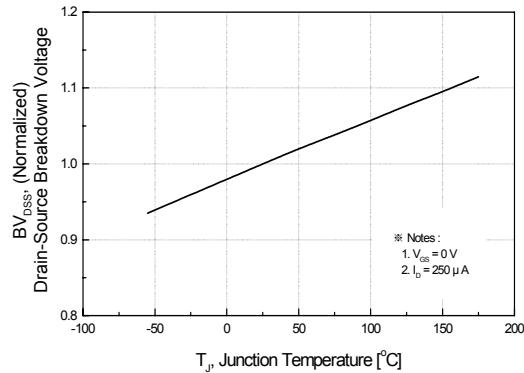


Fig 8. On-Resistance Variation vs. Junction Temperature

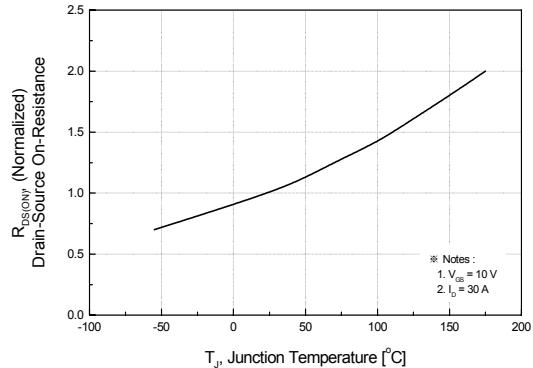


Fig 9. Maximum Safe Operating Area

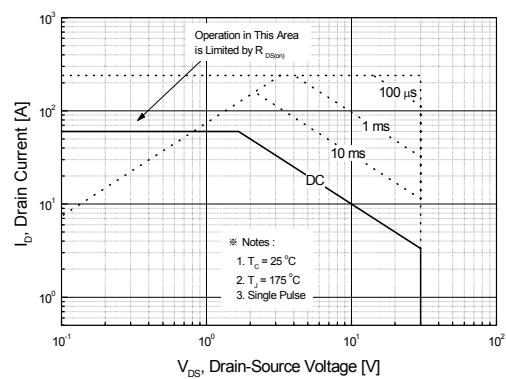


Fig 10. Maximum Drain Current vs. Case Temperature

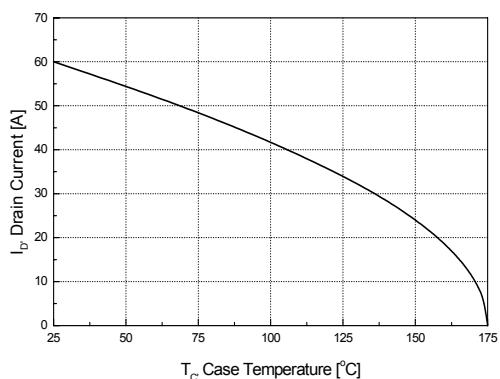
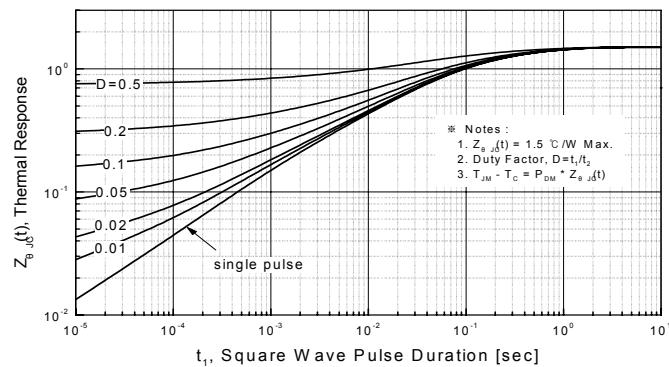


Fig 11. Transient Thermal Response Curve



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Fig. 12. Gate Charge Test Circuit & Waveforms

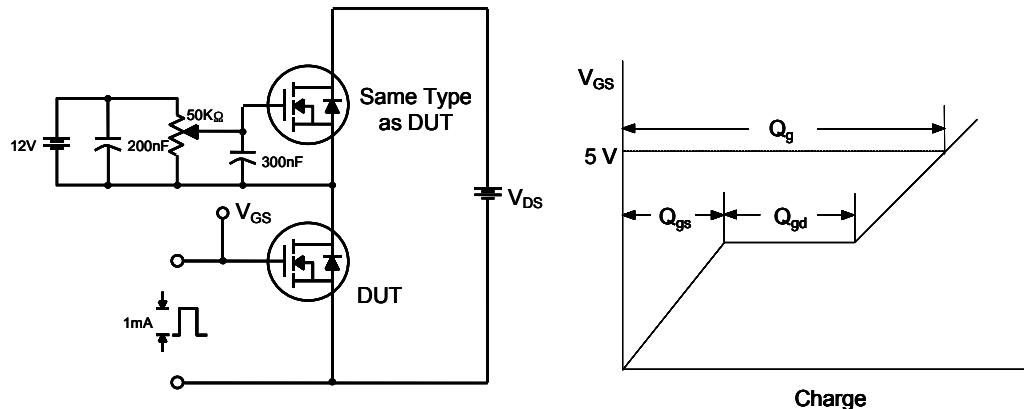


Fig 13. Switching Time Test Circuit & Waveforms

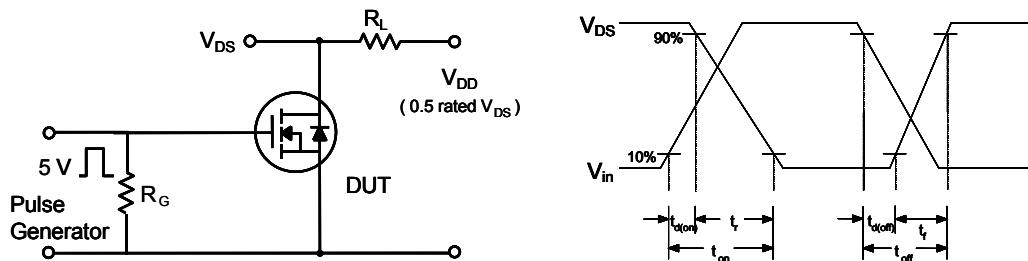
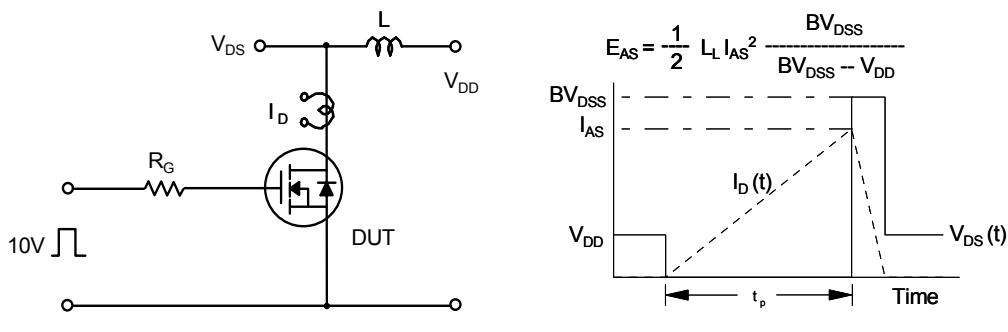
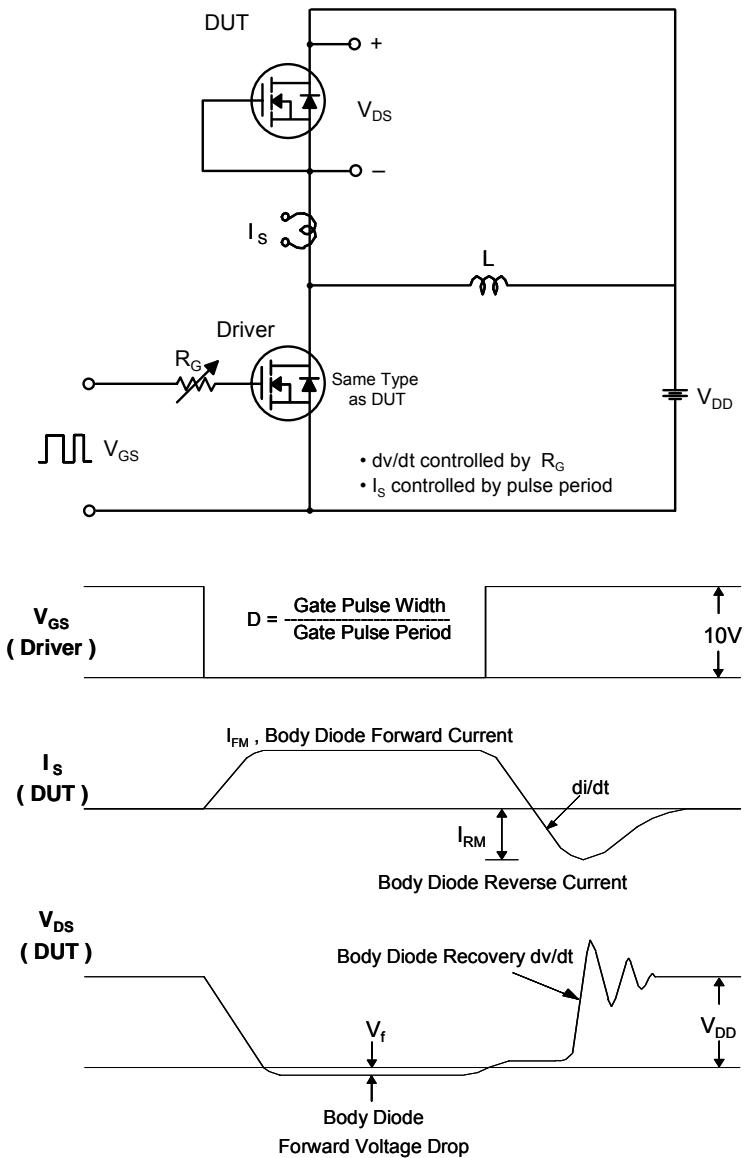


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms



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Fig. 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



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TO-263(D²-PAK) Package Dimension

Dim.	mm			Inch		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	9.8	10	10.2	0.386	0.394	0.402
B	7.9	8	8.1	0.311	0.315	0.319
C	11.2	11.8	12.4	0.441	0.465	0.488
D	4.3	4.5	4.7	0.169	0.177	0.185
E	1.25	1.3	1.4	0.049	0.051	0.055
F	1.0	1.2	1.4	0.039	0.047	0.055
G		2.54			0.1	
H		2.54			0.1	
I	2.24	2.54	2.84	0.088	0.1	0.112
J	2.2	2.4	2.6	0.087	0.094	0.102
K	0.45	0.5	0.6	0.018	0.02	0.024
L	0.7	0.8	0.9	0.028	0.031	0.035
ϕ		1.57			0.06	

